

PCN 09_0244: ADG819 Metal and Via Mask Qualification

Test	Standard	Conditions	Quantities
High Temperature Operating Life ¹	JEDEC <i>JESD22-A108</i>	1000hrs @ 125C biased	Complete
Early Life Failure	<i>MIL-STD-883,Method1015</i>	48hrs @125C biased	Complete
Highly Accelerated Stress Test (HAST) ¹	JEDEC <i>JESD22-A110</i>	96hrs @ 85%RH 131C biased	Complete
Temperature Cycle ¹	JEDEC <i>JESD22-A104</i>	500cycles -65C/+150C	Complete
Autoclave ¹	JEDEC <i>JESD22-A102</i>	96hrs @ 100%RH 121C unbiased	Complete
High Temperature Storage ¹	JEDEC <i>JESD22-A103</i>	1000hrs @ 150C	Complete
Latch-Up	JEDEC Standard 78	+25C & 125C Biased single duration 100/99mA	Complete
Electrostatic Discharge <i>Human Body Model</i>	ESD Association <i>STM5.1-2001</i>	Std Sample 1 Zap per polarity p/f 1000V/999V	26 Feb 2010
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	ESD Association <i>STM5.3.1-1999</i>	All pins 3 zaps per polarity p/f 500V/499V	26 Feb 2010